Jian-Yu (Jerry) Lin

Research Interests

- Semiconductor Physics and Devices
- Low Dimensional Materials & Devices
- Power Semiconductor Devices
- Compound Semiconductor Devices

Education

National Taiwan University (NTU)

M.S. IN ELECTRONICS ENGINEERING

• Overall GPA: 4.3/4.3

• Rank: 1/136 (1%)

National Taiwan University (NTU)

B.S. IN ELECTRICAL ENGINEERING

Overall GPA: 4.15/4.3Rank: 14/190 (7%)

Taipei, Taiwan

Taipei, Taiwan

09/2019 - 06/2021

09/2015 - 06/2019

Publication

Journal

1. <u>Jian-Yu Lin</u> and Jenn-Gwo Hwu, "Enhanced Transient Behavior in MIS(p) Tunnel Diodes by Trench Forming at the Gate Edge," *IEEE Transactions on Electron Devices*, vol. 68, no. 9, pp. 4189-4194, Sept. 2021, doi: 10.1109/TED.2021.3095052. [Github link]

Conference

- 1. <u>Jian-Yu Lin</u> and Jenn-Gwo Hwu, "Enhanced Memory Properties in MIS TD by Forming Trench Structure at the Gate Edge," 2020 International Electronic Devices and Materials Symposium (IEDMS), 5021, C1-3, Chang Gung University, Tao-Yuan City, Taiwan, ROC, Oct. 2020. (oral presentation) [Github link]
- 2. <u>Jian-Yu Lin</u> and Jenn-Gwo Hwu, "Dependency of Transient Current Behavior on Oxide Thickness in Trench Structure MIS TDs," 2021 International Electronic Devices and Materials Symposium (IEDMS), 1032, C3-1, National Cheng Kung University, Tainan City, Taiwan, ROC, Nov. 2021. (oral presentation, Best Paper Award) [Github link]

Patent

1. Jenn-Gwo Hwu and <u>Jian-Yu Lin</u>, "MIS-TD Memory with Shallow Trench Edge Passivation Structure," under application through Taiwan Semiconductor Manufacturing Company (TSMC) and NTU.

Research Experience

Capacitance-Voltage Lab, NTU

Taipei, Taiwan

Graduate and Undergraduate Research Assistant (with Prof. Jenn-Gwo Hwu)

09/2018 - Present

- 1. Enhanced Memory Property in Trench Structure Metal-Insulator-Semiconductor (MIS) Tunnel Diode (TD) with Thin Oxide (2.5 nm) (Conference #1)
 - Designed new device structure for MIS TDs, called **trench structure MIS TDs** (abbreviated as Trench MIS).
 - Improved memory property, current window (CW), of MIS TDs by utilizing **defects and traps** at trench structure.
 - Achieved **5 times larger CW** in Trench MIS devices compared to normal structure MIS TDs (abbreviated as Planar MIS) in long time (>10 s) voltage stress memory endurance measurements.
- 2. Enhanced Transient Current in Trench Structure MIS TD with Thick Oxide (≥ 2.8 nm)
 - Investigated stronger transient currents in Trench MIS compared to them in Planar MIS.
 - Proposed that **weaker oxide electric field** in Trench MIS is the reason for enhanced transient currents.
 - Utilized Trench MIS as memory devices by using different transient currents of MIS TDs to store memory data.
 - Accomplished **25 times larger CW** in Trench MIS compared to that in Planar MIS devices in short time (1 ms) voltage pulse memory endurance measurements. (**Journal #1**)
 - Examined dependency of transient current on oxide thickness in Trench MIS. (Conference #2)

Quantum Electronics Lab, NTU

Taipei, Taiwan

Undergraduate Researcher (with Prof. Jiun-Yun Li)

09/2017 - 08/2018

- GeSn Band Structure Calculations using Empirical Pseudopotential Method (EPM)
 - Calculated band structure of Si, Ge, and GeSn based on a program called Sentaurus Band Structure.
 - Adopted virtual crystal approximation to adjust Sn to Ge ratios in GeSn band structure calculations.

Work Experience

EEE5057: Memory Circuit Technology, NTU

Teaching Assistant (with Prof. Vita Pi-Ho Hu)

EE3013: Solid State Electronics, NTU

Teaching Assistant (with Prof. Jenn-Gwo Hwu)

5 nm Device Department, Taiwan Semiconductor Manufacturing Company (TSMC)

R&D Device Engineer, Summer Internship program (supervised by Dr. Chien-Tai Chan)

- Evaluated interface state density (D_{it}) of FinFETs by charge pumping (CP) method.
- Implemented CP measurements via TSMC's wafer acceptance test (WAT) computer programs, which are used by engineers to carry out electrical measurements.
- Authored an instruction document about how to analyze average and energy profiles of D_{it} using my WAT programs.
- Finalist in the R&D group of the 2019 TSMC Summer Internship Competition (top 15% among all R&D interns).

Skills

Semiconductor Fabrication

- Radio Cooperation of America (RCA) clean
- Anodic oxidation
- Rapid thermal annealing (RTA)
- Furnace annealing
- Thermal evaporation

Electrical Measurement

- Agilent B1500A semiconductor device
 analyzer
- Capacitance-voltage (C-V)
- Current-voltage (I-V)

Software

- Silvaco technology computer-aided design (TCAD) simulation
- OriginLab
- **Equipment Management**
- Thermal evaporator

- Optical lithography
- Wet etching
- Reactive ion etching (RIE)

Taipei, Taiwan

Taipei, Taiwan

03/2021 - 06/2021

10/2020 - 01/2021

Hsinchu, Taiwan

07/2019 - 08/2019

- · DC sputtering
- · Lift-off process
- Current/Voltage-time (I/V-t)
- Memory endurance & retention measurement
- Python
- Matlab
- LaTeX

Honors & Awards

2021 Best Paper Award, 2021 International Electronic Devices and Materials Symposium (IEDMS)

Out of 22 orally-presented papers.

2021 Honorary Member of Phi Tau Phi Scholastic Honor Society

Academic performance with rank top 3% among master's graduands in the college.

2020-2021 TSMC-NTU Research Center Research Assistant Scholarship (for master student)

Given by TSMC each year to students at NTU based on their academic and research performance.

2019 Course completion, Applied Materials - Advanced Technologies of Semiconductor and Display

A course of study offered by Applied Materials Taiwan at NTU.

2019 Finalist (top 10) in R&D group of 2019 TSMC Summer Internship Competition

Based on project results and presentation skills (top 15% of all R&D interns).

2019 Presidential Award, Department of Electrical Engineering, NTU

Given each semester to students' ranking within the top 5% of their class (Rank: 1/203 at Spring'19).

2017-2019 TSMC-NTU Research Center Research Assistant Scholarship (for undergraduate), 4 times

Given by TSMC each semester to students at NTU based on their academic and research performance.

Language

English Proficiency (TOEFL)

• Date: 2021/2/28

• Total score = 108

R/L/S/W = 29/29/23/27

GRE

• Date: 2020/11/28

• V/Q = 158/170

• AWA = 3.5

References

- 1. Prof. Jenn-Gwo Hwu (graduate and undergraduate research advisor), email: jghwu@ntu.edu.tw
- 2. **Prof. Jiun-Yun Li (undergraduate research advisor)**, email: jiunyun@ntu.edu.tw
- 3. **Dr. Chien-Tai Chan (intern supervisor and senior manager in Device Dept., N2 Platform Development Div., TSMC)**, email: ct_chan@tsmc.com